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The product described in this document has not been fully tested to ensure conformance to the requirements outlined below. Therefore, TE Connectivity (TE) makes no representation or warranty, express or implied, that the product will comply with these requirements. Further, TE may change these requirements based on the results of additional testing and evaluation. Contact TE Engineering for further details.

Discrete Magnetics

1. SCOPE

1.1. Content

This specification covers the performance, tests and quality requirements for Discrete Magnetics for Ethernet applications.

1.2. Qualification

When tests are performed on the subject product line, procedures specified in Paragraph 3.3 shall be used. All inspections shall be performed using the applicable inspection plan and product drawing.

2. APPLICABLE DOCUMENTS AND FORMS

The following documents and forms constitute a part of this specification to the extent specified herein.

2.1. TE Documents

A. Application Specifications

114-94555 Application Specification

B. Test Reports

501-19265 Engineering Report

2.2. Standards

IEEE 802-3 Local Area Networks: Carrier Sense Multiple Access with Collision Detection

(CSMA/CD) Access Method and Physical Layer Specification

MIL-STD-202 Test Methods for Electronic and Electrical Component Parts

General – Applicable publications

ETSI EN 300 019 Environmental Conditions and Environmental Tests for Telecommunications

Equipment

3. REQUIREMENTS

3.1. Design and Construction

Product shall be of the design, construction, materials and physical dimensions specified on the applicable product drawing.



3.2. Materials

Materials used in the construction of this product shall be as specified on the applicable product drawing.

	SMT Parts	THT Parts		
Lead Frame / THT Lead	C5191-HV170-190°	CP Wire		
Cover	LCP Black, UL-94-V0	Black PF2A5-151J, UL-94-V0		
Header	Black WH-9100, UL-94-V0	Black PF2A5-151J, UL-94-V0		
Magnetics	Common mode choke cores, Isolation transformer cores. Wound cores consist of magnet wire winding on a manganese-zinc ferrite toroid.			

3.3. Test Requirements and Procedures Summary

Unless otherwise specified, all tests shall be performed at ambient environmental conditions.

TEST DESCRIPTION	REQUIREMENT	PROCEDURE		
Visual examination	Meet requirements of product drawing. There shall be no cracks or burrs	comply with IEC 60512-1-1 Test 1a		
Coplanarity	< 0.1mm	EIA-364-18B		
ELECTRICAL				
HI Pot (Isolation voltage)	1500 VAC / 10mA for 60s	Between the contacts on the jack side		
	No flashovers may occur visually or audibly on the sample or any breackdowns with a maximum allowed of current 2mA.	and the contacts on the PHY side.		
	Comply with IEEE802.3 isolation requirements: IEC 60512-4-1 Test 4a			
Turn ratio (Chip: cable)	TX = 1:1; RX = 1:1 @100kHz, 100mV	Define by chipset		
POE+	The temperature should not exceed 85°C on 1A Comply with IEEE802.3at	In accordance with IEEE802.3at		
MECHANICAL				
Vibration	No physical evidence of damage	ETSI 300 019 Class 2.2		
		Displacement: 3,5 mm		
		Acceleration: 15 m/s ²		
		Frequency range: 9 – 200 Hz		
		Sweep cycles: 3×5		
		Duration: 30 min		
ENVIRONMENTAL				
Thermal shock	No physical evidence of damage	MIL-STD-202-107		
		$T_a = -40$ °C $t_a = 30 \text{ min}$		
		$T_b = +125^{\circ} \text{ C}$ $t_b = 30 \text{ min}$		
		Number of cyles: 5		

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TRANSMISSION PERFORMANCE

Insertion Loss	-1.0 dB MAX, from 1 MHz to 100 MHz	In accordance with IEC 60512-27-100	
IIISEILIOII LOSS	-1.0 db MAX. IIOIII 1 MHZ to 100 MHZ	in accordance with IEC 60312-27-100	
Return Loss	-18 dB MIN. from 1 MHz to 30 MHz	In accordance with IEC 60512-27-100	
	-14.4 dB MIN. at 40 MHz		
	-13.1 dB MIN. at 50 MHz		
	-12 dB MIN. at 80 MHz		
	-10 dB MIN. at 100 MHz		
Cross-Talk	-40 dB MIN. at 30 MHz	In accordance with IEC 60512-27-100	
	-35 dB MIN. at 60 MHz		
	-30 dB MIN. at 100 MHz		
Common- to- Common Mode Attenuation	-40 dB MIN. at 30 MHz	In accordance with IEC 60512-27-100	
	-35 dB MIN. at 60 MHz		
	-30 dB MIN. at 100 MHz		
DC Resistance	1.2 Ohms MAX.		
SOLDERABILITY			
Solderability test	The part must be solderable using the applicable JEDEC profile (STD-20D for SMT)	MIL-STD-202-208	
	THT part must be solderable using Wave Soldering process:		
	Max. temp = $+260 \pm 5^{\circ}$ C, 10 ± 1 s		

NOTE

Shall meet visual requirements, show no physical damage, and meet requirements of additional tests as specified in the Product Qualification and Requalification Test Sequence shown in Paragraph 3.4.

3.4. Test Sequence of product qualification

TEST OR EXAMINATION	TEST GROUP				
	I	II	III	IV	V
Visual examination	1,9 ^(a)	1,4	1,4	1,3	1,3
HI Pot (Isolation voltage)	7				
Turn ratio (Chip: cable)	2				
DC Resistance	8	3	3		
POE+					2
Vibration		2			
Thermal shock			2		
Insertion Loss	3				
Return Loss	4				
Near-End Cross-Talk (NEXT)	5				
Common-to-Common Mode Attenuation	6				
Solderability test				2	

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(a) Numbers indicate sequence in which tests are performed.

4. QUALITY ASSURANCE PROVISIONS

4.1. Qualification Testing

A. Sample Selection

The samples shall be prepared in accordance with product drawings. They shall be selected at random from current production.

B. Test Sequence

The tests realization must be in accordance with test groups as shown in section 3.4.

4.2. Re-Qualification Testing

If changes significantly affecting form, fit, or function are made to the product or to the manufacturing process, product assurance shall coordinate requalification testing, consisting of all or part of the original testing sequence as determined by development/ product, quality, and reliability engineering.

4.3. Acceptance

Acceptance is based on verification that the product meets the requirements of section 3.3. Failures attributed to equipment, test setup, or operator deficiencies shall not disqualify the product. When product failure occurs, corrective action shall be taken, and samples resubmitted for qualification. Testing to confirm corrective action is required before resubmittal.

4.4. Quality Conformance Inspection

The applicable TE quality inspection plan will specify the sampling acceptable quality level to be used. Dimensional and functional requirements shall be in accordance with the applicable product drawing and this specification.

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